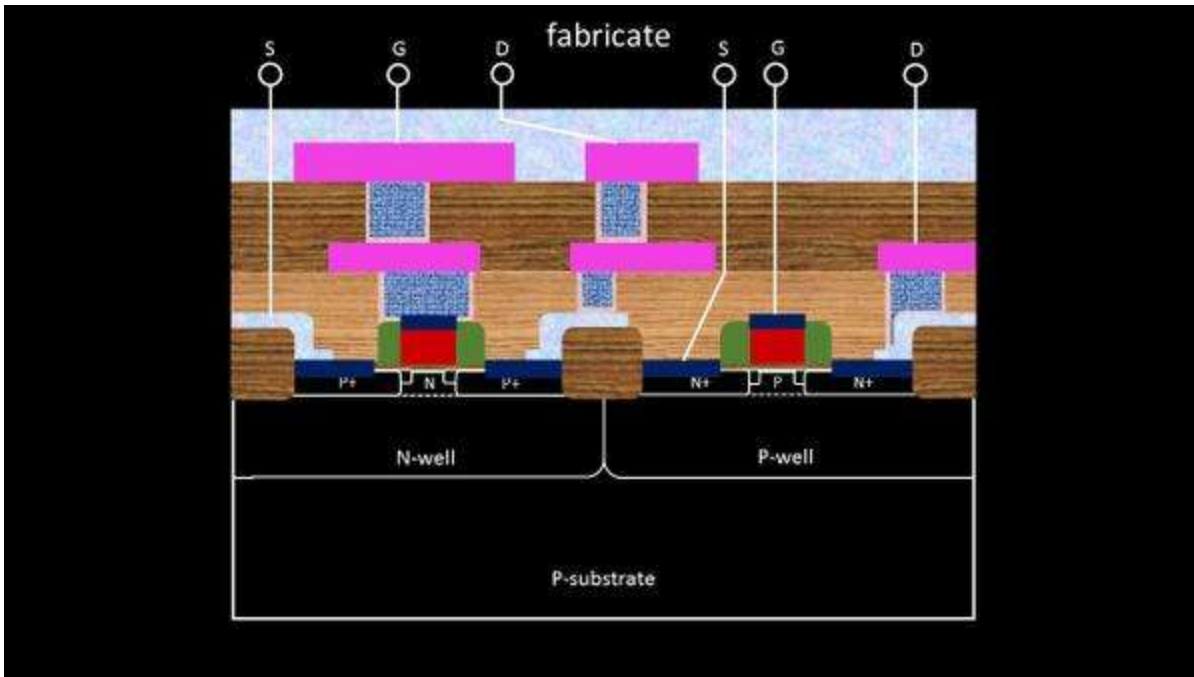




16-mask process

Looks complex. not anymore!!

Kunal Ghosh



If you consider the above image, and wondering how complex it is to build and package a chip, you will change your opinion after the 16-masks that I would show in this and following blogs

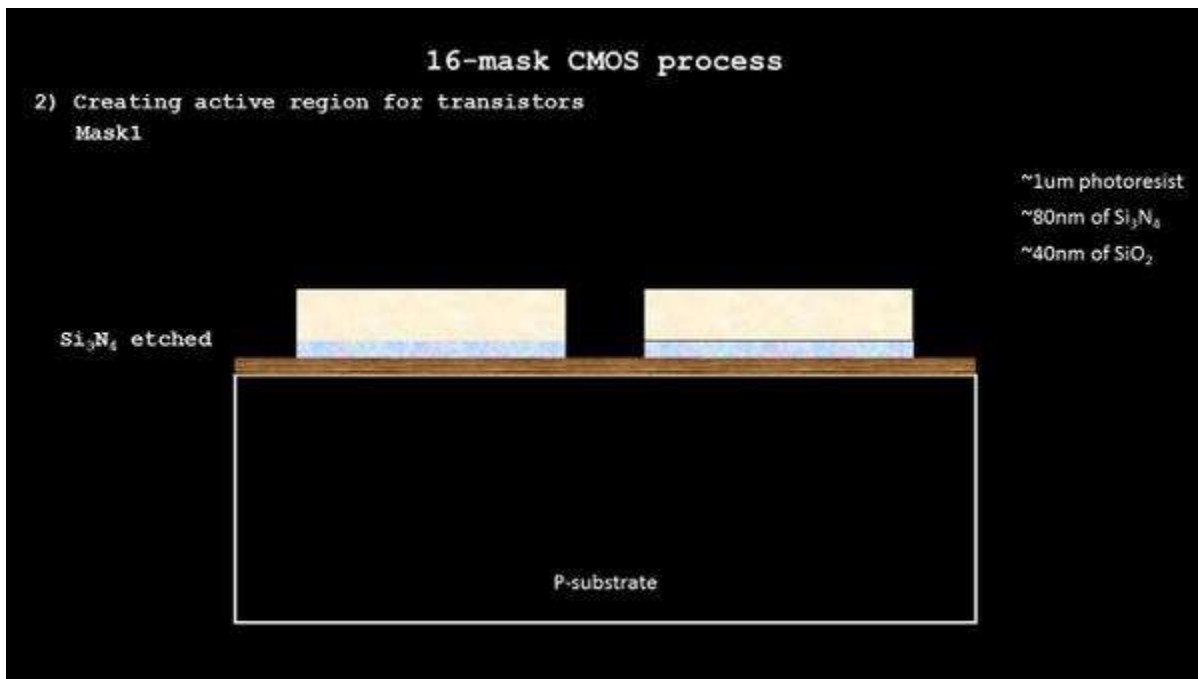
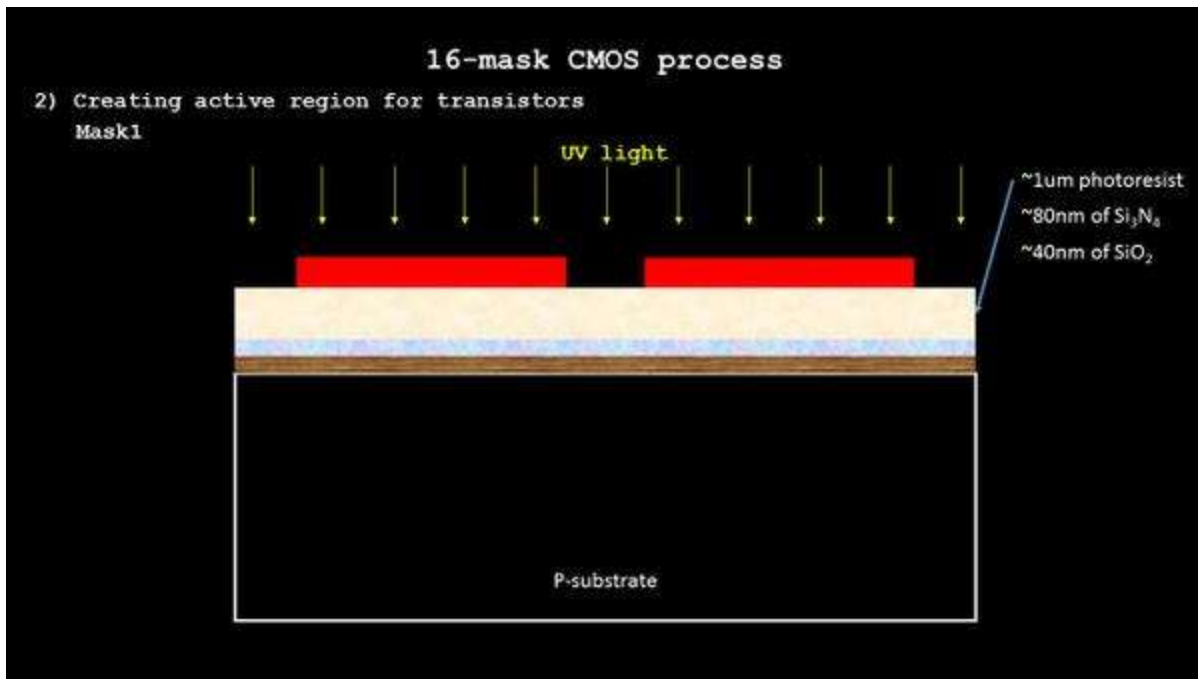
Note: The 16-mask process is also covered in detail in my new course, for which the link is below:

<https://www.udemy.com/vlsi-academy-custom-layout>

Let's skip some process steps and consider 1st mask below:

This is to create the active regions to build pmos/nmos transistors...will be evident as we move forward.

So, the mask is an opaque plate which blocks the UV light to react with certain areas of photo-resist. As shown above, part of resist is exposed to UV light, which gets washed away giving us the below open areas for further process steps, to etch away Si₃N₄:



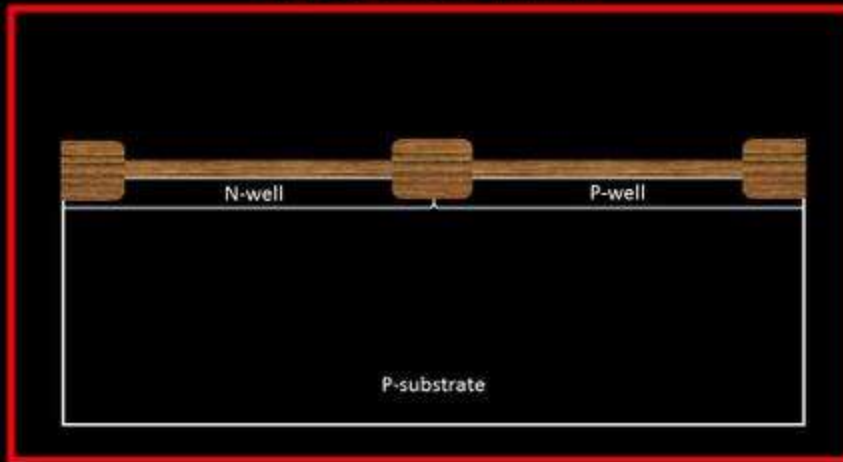
Active regions are isolated from each other using isolation SiO_2 (shown in below image), which is grown with 'LOCOS' technique (**L**ocal **O**xidation of **S**ilicon).

Mask2 and Mask3 will be used to create wells (nwell for pmos and pwell for nmos) as shown in below images:

16-mask CMOS process

3) N-Well and P-Well formation

High temperature furnace

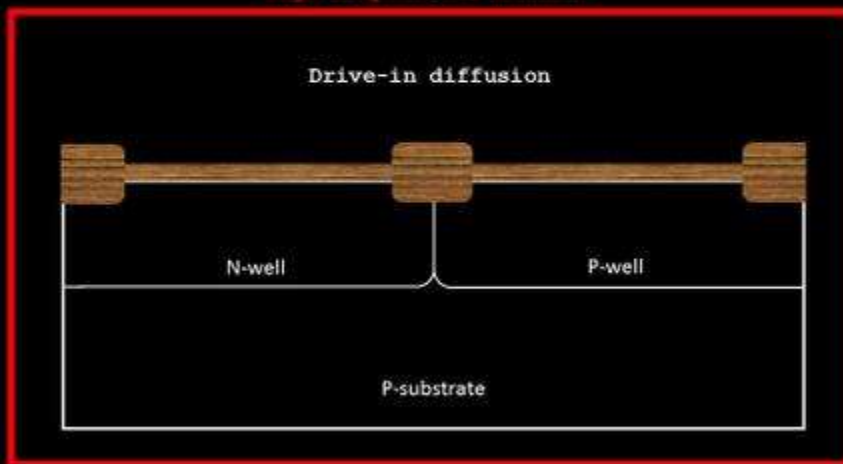


16-mask CMOS process

3) N-Well and P-Well formation

High temperature furnace

Drive-in diffusion



Next we fabricate the most important terminal of MOS transistor i.e. gate terminal... Remember from one of my [‘Circuit design and SPICE simulation’](#) course, I had talked about some important parameters that’s helpful in tuning the threshold voltage. Below image shows the same: It’s the ‘doping concentration’ and ‘oxide capacitance’

Threshold Voltage Equation:

$$V_t = V_{t0} + \gamma(\sqrt{|-2\phi_f + V_{sb}|} - \sqrt{|-2\phi_f|})$$

Where

V_{t0} = Threshold voltage at $V_{sb} = 0$, and is a function of manufacturing process

γ = body effect coefficient, expresses the impact of changes in body bias V_{sb} (Unit is $V^{0.5}$)

ϕ_f = Fermi Potential

$$\gamma = \frac{\sqrt{2qNA_s\epsilon_{si}}}{C_{ox}}$$

2 important terms for gate formation, as they control V_t

ϵ_{si} = relative permittivity of silicon = 11.7

N_A = doping concentration

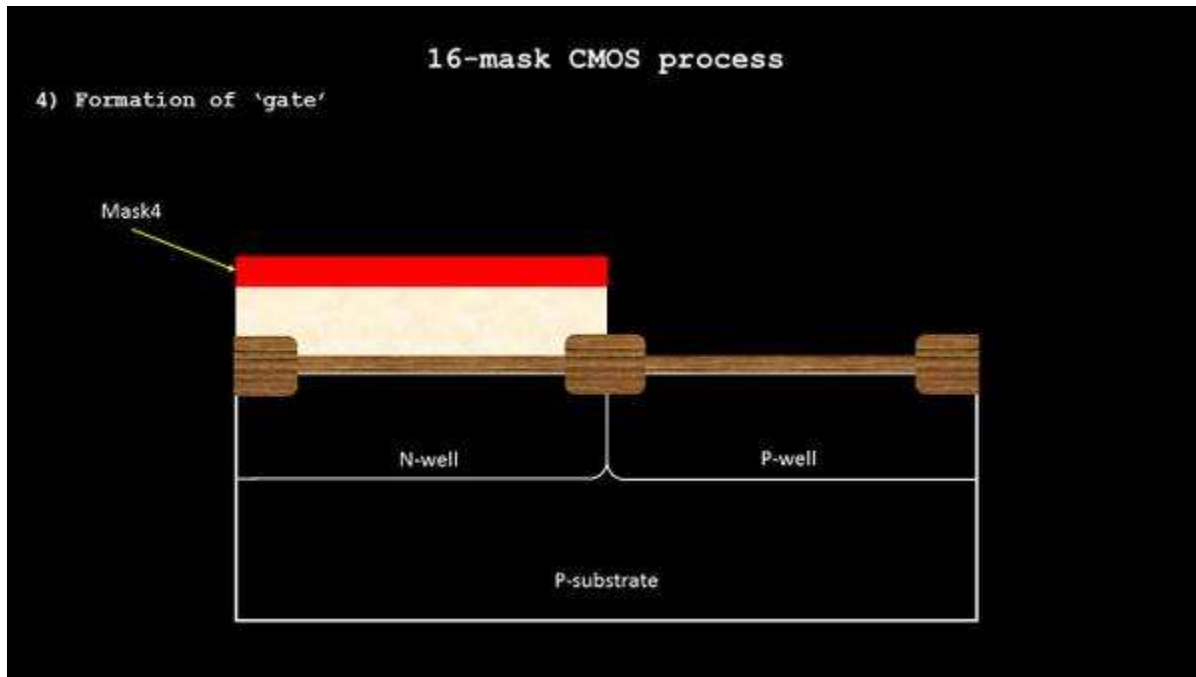
q = charge of the electron

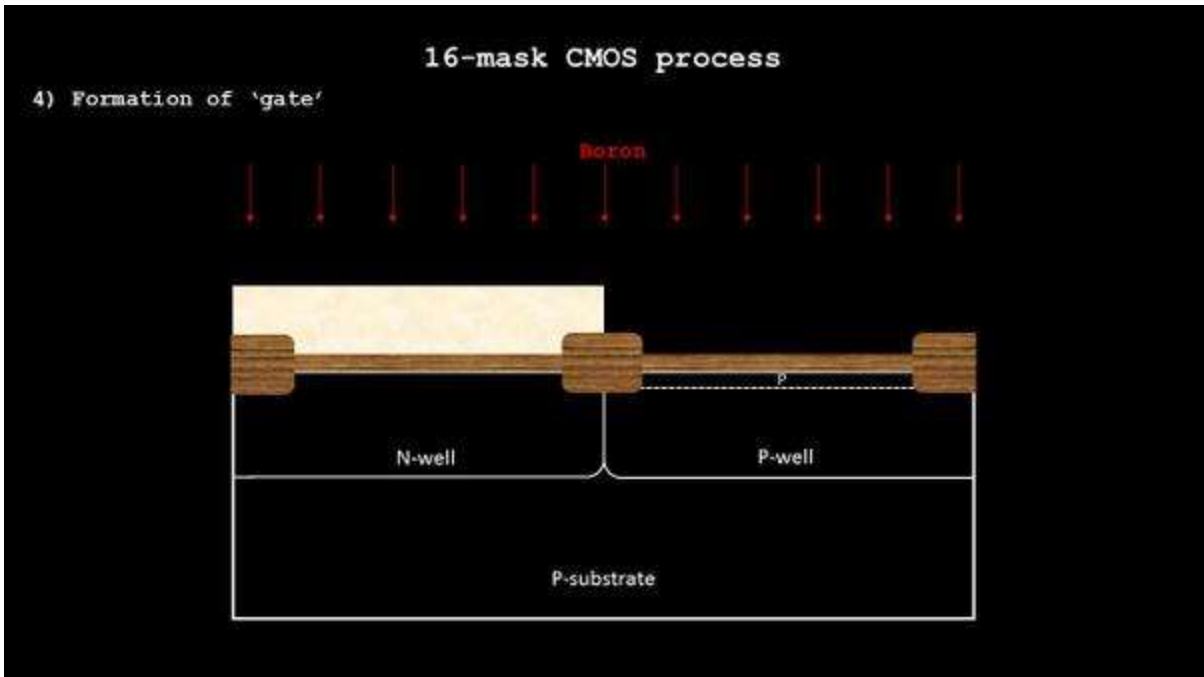
C_{ox} = oxide capacitance

$$\phi_f = -\phi_T + \ln \frac{N_A}{n_i}$$

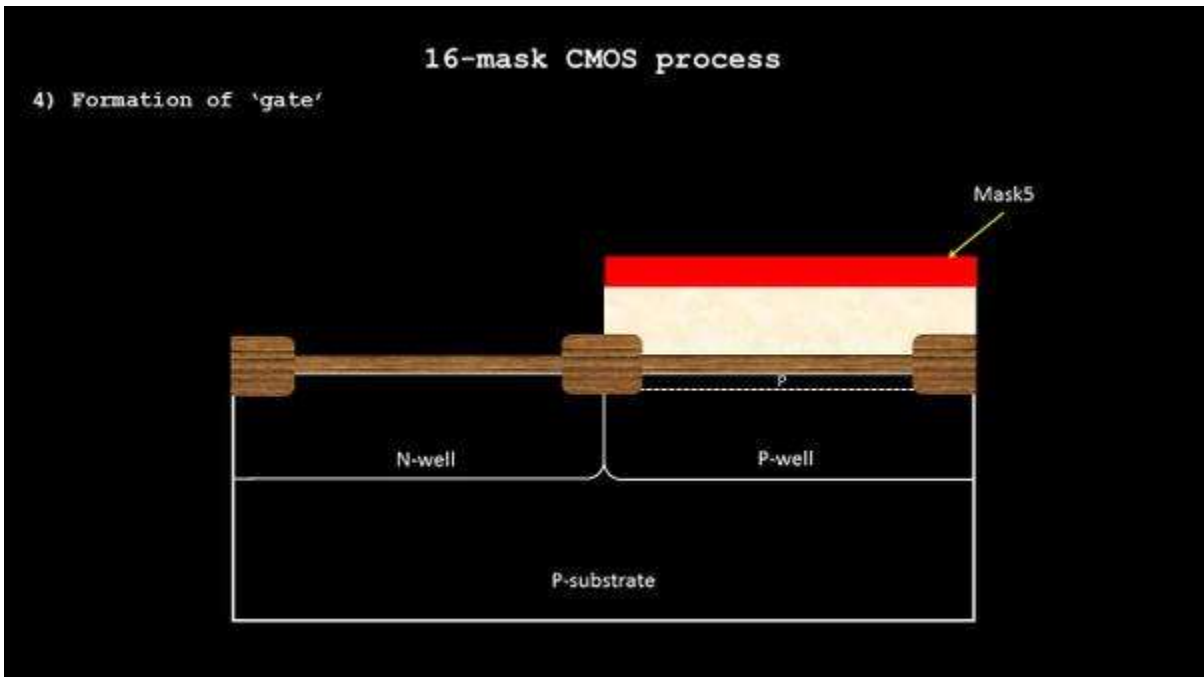
n_i = intrinsic doping parameter for the substrate

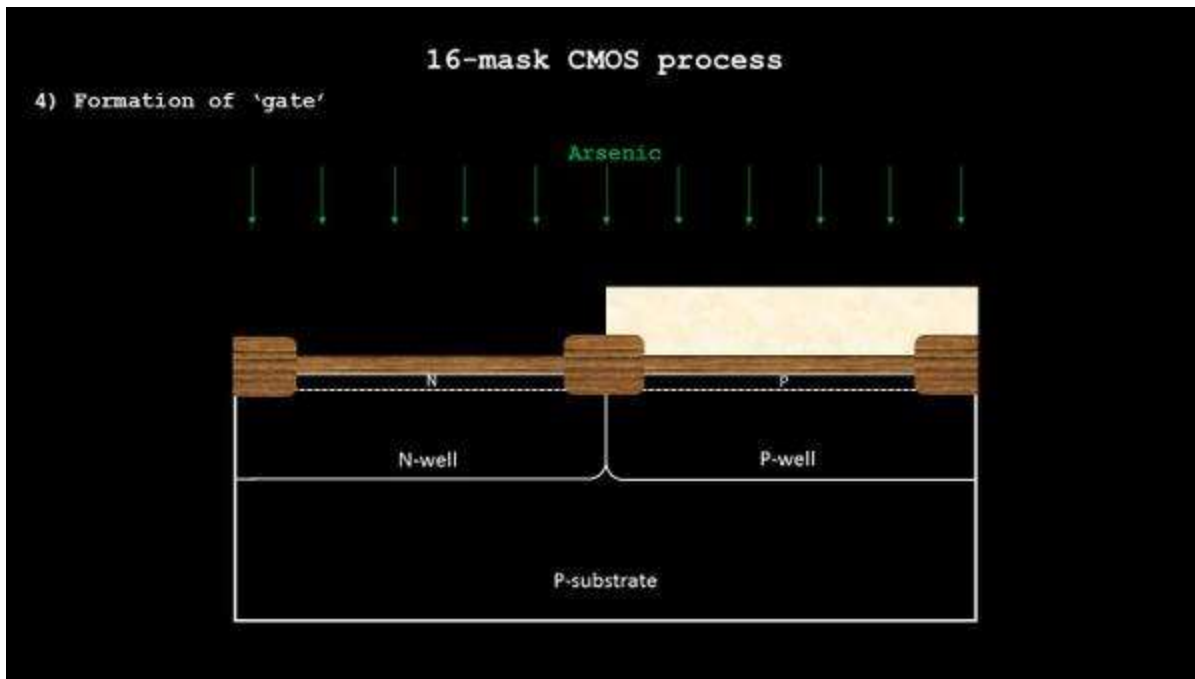
Let's see how do we attain that. And here's mask4 that helps block nwell region and dope p-well with p-type impurity i.e. boron, as shown in below images:





Similarly, we dope nwell with n-type impurity i.e. Arsenic and use mask 5 for the same as shown in below images:





The oxide present has been through lot of processes like n-type impurity doping, p-type impurity doping, nwell formation, pwell formation and so on, due to which its quality gets reduced. So, the original oxide is stripped off using HF acid and then re-grown to give high quality oxide, as shown in below image. This also helps in controlling oxide capacitance, a key parameter to control threshold voltage

